

<b>Notice of References Cited</b>	Application/Control No. 10/040,402	Applicant(s)/Patent Under Reexamination SHIRAIWA, YOSHINOBU	
	Examiner, Huan H. Tran	Art Unit 2861	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-198551	07-1999	Japan	Shirawa et al	B41M005/38
	O	JP 11-198594	07-1999	Japan	Sasaki et al.	B41M005/38
	P					
	Q					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Translation of JP 2000-218887
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